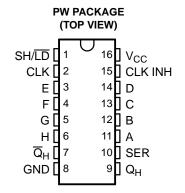
www.ti.com

SCLS694-JANUARY 2006

FEATURES

- Controlled Baseline
 - One Assembly/Test Site, One Fabrication Site
- Extended Temperature Performance of –55°C to 125°C
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree (1)
- 2-V to 5.5-V V_{CC} Operation
- Max t_{nd} of 10.5 ns at 5 V
- Supports Mixed-Mode Voltage Operation on All Ports
- I_{off} Supports Partial-Power-Down Mode Operation
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- (1) Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)



DESCRIPTION

The SN74LV165A-EP is a parallel-load, 8-bit shift register designed for 2-V to 5.5-V V_{CC} operation.

When the device is clocked, data is shifted toward the serial output Q_H . Parallel-in access to each stage is provided by eight individual direct data inputs that are enabled by a low level at the shift/load (SH/ \overline{LD}) input. The SN74LV165A-EP features a clock-inhibit function and a complemented serial output, Q_H .

Clocking is accomplished by a low-to-high transition of the clock (CLK) input while SH/LD is held high and clock inhibit (CLK INH) is held low. The functions of CLK and CLK INH are interchangeable. Since a low CLK and a low-to-high transition of CLK INH accomplishes clocking, CLK INH should be changed to the high level only while CLK is high. Parallel loading is inhibited when SH/LD is held high. The parallel inputs to the register are enabled while SH/LD is held low, independently of the levels of CLK, CLK INH, or SER.

This device is fully specified for partial-power-down applications using I_{off} . The I_{off} circuitry disables the outputs, preventing damaging current backflow through the devices when they are powered down.

ORDERING INFORMATION

T _A	PACKAGE ⁽¹⁾		ORDERABLE PART NUMBER	TOP-SIDE MARKING	
-55°C to 125°C	TSSOP – PW	Reel of 2000	SN74LV165AMPWREP	LV165EP	

(1) Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



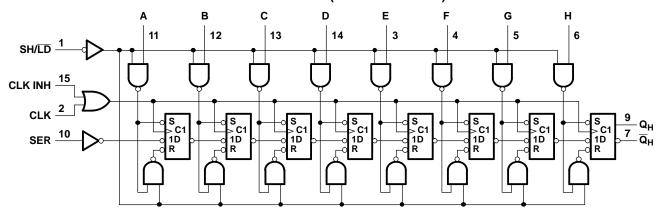
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



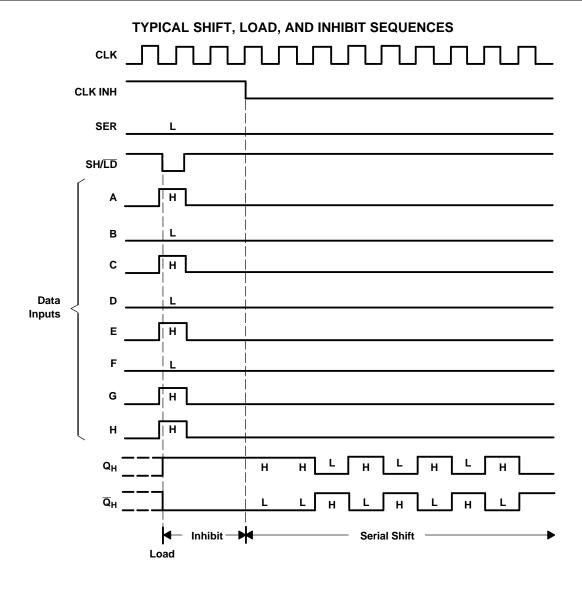
FUNCTION TABLE

	INPUTS		OPERATION
SH/LD	CLK	CLK INH	OPERATION
L	X	X	Parallel load
Н	Н	X	Q_0
Н	X	Н	Q_0
Н	L	1	Shift
Н	\uparrow	L	Shift

LOGIC DIAGRAM (POSITIVE LOGIC)







SN74LV165A-EP PARALLEL-LOAD 8-BIT SHIFT REGISTER

SCLS694-JANUARY 2006



Absolute Maximum Ratings⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V_{CC}	Supply voltage range		-0.5	7	V
VI	Input voltage range ⁽²⁾		-0.5	7	V
Vo	Voltage range applied to any output in the high-impedance or power-off state (2)			7	V
Vo	Output voltage range ⁽²⁾⁽³⁾		-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	V _I < 0		-20	mA
I _{OK}	Output clamp current	V _O < 0		-50	mA
IO	Continuous output current	$V_O = 0$ to V_{CC}		±25	mA
	Continuous current through V _{CC} or GND			±50	mA
θ_{JA}	Package thermal impedance (4)			108	°C/W
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

Recommended Operating Conditions(1)

			MIN	MAX	UNIT	
V _{CC}	Supply voltage		2	5.5	V	
		V _{CC} = 2 V	1.5			
	High level input valtage	V _{CC} = 2.3 V to 2.7 V	$V_{CC} \times 0.7$		V	
V _{IH}	High-level input voltage	V _{CC} = 3 V to 3.6 V	$V_{CC} \times 0.7$		V	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	$V_{CC} \times 0.7$			
		V _{CC} = 2 V		0.5		
V	Low level input valtage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		$V_{CC} \times 0.3$	V	
V _{IL}	Low-level input voltage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		$V_{CC} \times 0.3$	V	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		$V_{CC} \times 0.3$		
VI	Input voltage		0	5.5	V	
Vo	Output voltage		0	V_{CC}	V	
		V _{CC} = 2 V		-50	μA mA	
	High level subject support	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		-2		
I _{OH}	High-level output current	$V_{CC} = 3 V \text{ to } 3.6 V$		-6		
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		-12		
		V _{CC} = 2 V		50	μΑ	
	Low-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		2		
I _{OL}	Low-level output current	$V_{CC} = 3 V \text{ to } 3.6 V$		6	mA	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		12		
		V _{CC} = 2.3 V to 2.7 V		200		
Δt/Δν	Input transition rise or fall rate	V _{CC} = 3 V to 3.6 V		100	ns/V	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		20		
T _A	Operating free-air temperature		-55	125	°C	

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

⁽²⁾ The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.

⁽³⁾ This value is limited to 5.5 V maximum.

⁽⁴⁾ The package thermal impedance is calculated in accordance with JESD 51-7.



Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT			
	$I_{OH} = -50 \mu A$	2 V to 5.5 V	V _{CC} - 0.1						
V	$I_{OH} = -2 \text{ mA}$	2.3 V	2			V			
V _{OH}	$I_{OH} = -6 \text{ mA}$	3 V	2.48			V			
	$I_{OH} = -12 \text{ mA}$	4.5 V	3.8						
	$I_{OL} = 50 \mu A$	2 V to 5.5 V			0.1	V			
V	I _{OL} = 2 mA	2.3 V			0.4				
V _{OL}	I _{OL} = 6 mA	3 V			0.44				
	I _{OL} = 12 mA	4.5 V			0.55				
I _I	V _I = 5.5 V or GND	0 to 5.5 V			±1	μΑ			
I _{cc}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			20	μΑ			
I _{off}	V_I or $V_O = 0$ to 5.5 V	0			5	μΑ			
C _i	V _I = V _{CC} or GND	3.3 V		1.7		pF			

Timing Requirements

over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

			T _A = 25	25°C	MIN	MAY	UNIT	
			MIN	MAX	IVIIIN	MAX	UNII	
	Pulse duration	CLK high or low	8.5		9			
t _w	tw Fuise duration	SH/LD low	11		13		ns	
		SH/LD high before CLK↑	7		8.5			
	Catur time	SER before CLK↑	8.5		9.5			
t _{su}	Setup time	CLK INH before CLK↑	7		7		ns	
		Data before SH/LD↑	11.5		12			
		SER data after CLK↑	-1		0			
t _h	Hold time	Parallel data after SH/LD↑	0		0.5		ns	
		SH/LD high after CLK↑	0		0			

Timing Requirements

over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

			T _A = 25°C	MIN	MAX	UNIT
			MIN MA	X	IVIAA	UNIT
	Pulse duration	CLK high or low	6	7		20
t _w	t _w Fulse duration	SH/LD low	7.5	9		ns
		SH/LD high before CLK↑	5	6		
	Cotup time	SER before CLK↑	5	6		20
t _{su}	Setup time	CLK INH before CLK↑	5	5		ns
		Data before SH/LD↑	7.5	8.5		
		SER data after CLK↑	0	0		
t _h	t _h Hold time	Parallel data after SH/LD↑	0.5	0.5		ns
		SH/LD high after CLK↑	0	0		

SN74LV165A-EP PARALLEL-LOAD 8-BIT SHIFT REGISTER

SCLS694-JANUARY 2006



Timing Requirements

over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

			T _A = 25°C	С	MIN MAX		UNIT		
			MIN	MAX	IVIIN	WAX	UNIT		
	Pulse duration	CLK high or low	4		6.5				
t _w	, Fuise duration	SH/LD low	5		6.5		ns		
		SH/LD high before CLK↑	4		4				
	Cotup time	SER before CLK↑	4		4		no		
t _{su}	Setup time	CLK INH before CLK↑	3.5		4.5		ns		
		Data before SH/LD↑	5		5				
		SER data after CLK↑	0.5		0.5				
t _h	t _h Hold time	Parallel data after SH/LD↑	1		1		ns		
		SH/ LD high after CLK↑	0.5		0.5				

Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	то	LOAD CAPACITANCE	T _A = 25°C			MIN MAX	UNIT	
		(OUTPUT)		MIN	TYP	MAX	IVIIIN	IVIAA	UNII
f _{max}			C _L = 50 pF	40	65		35		MHz
	CLK				15.3	23.3	1	26	
t _{pd}	SH/LD	Q_H or \overline{Q}_H	$C_{L} = 50 \text{ pF}$		16.1	25.1	1	28	ns
pu .	Н				15.9	25.3	1	28	

Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	T _A = 25°C			MIN MAX	MAY	UNIT
PARAMETER				MIN	TYP	MAX	IVIIIN	IVIAA	UNIT
f _{max}			C _L = 50 pF	60	90		50		MHz
	CLK				10.9	14.9	1	16.9	
t _{pd}	SH/LD	Q_H or \overline{Q}_H	$C_{L} = 50 \text{ pF}$	·	11.3	19.3	1	22	ns
	Н			 ,	11.1	17.6	1	20	

Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	FROM TO	LOAD CAPACITANCE	T _A = 25°C			MIN MAX	UNIT	
PARAMETER		(OUTPUT)		MIN	TYP	MAX	IVIIIN		UNIT
f _{max}			$C_L = 50 pF$	75	85		75		MHz
	CLK			·	7.7	11.9	1	13.5	
t _{pd}	SH/LD	Q_H or \overline{Q}_H	$C_{L} = 50 \text{ pF}$		7.7	11.9	1	13.5	ns
	Н				7.6	11	1	12.5	

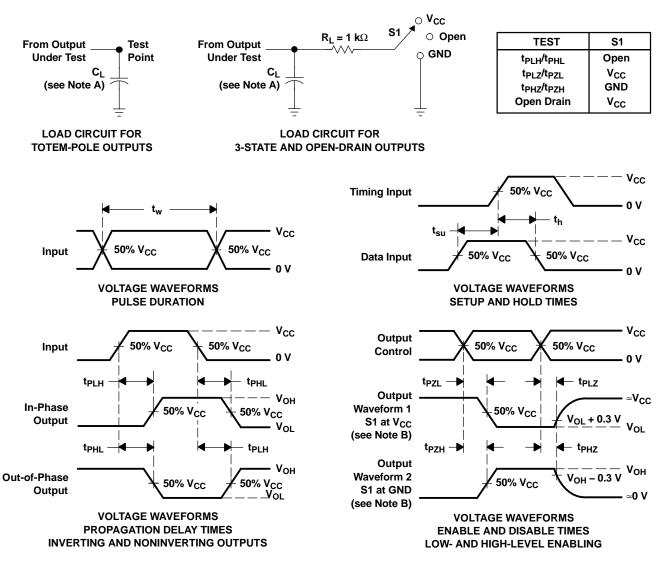
Operating Characteristics

 $T_A = 25^{\circ}C$

PARAMETER		TEST CONDITIONS	V _{CC}	TYP	UNIT
C _{pd}	Dower dissipation consistence	$C_1 = 50 \text{ pF}.$ $f = 10 \text{ MHz}$	3.3 V	36.1	pF
	Power dissipation capacitance	$C_L = 50 \text{ pF}, f = 10 \text{ MHz}$	5 V	37.5	



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis}.
- F. t_{PZL} and t_{PZH} are the same as t_{en} .
- G. t_{PHL} and t_{PLH} are the same as t_{pd}.
- H. All parameters and waveforms are not applicable to all devices.

Figure 1. Load Circuits and Voltage Waveforms

11-Nov-2025 www.ti.com

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
SN74LV165AMPWREP	Obsolete	Production	TSSOP (PW) 16	-	-	Call TI	Call TI	-55 to 125	LV165EP

⁽¹⁾ Status: For more details on status, see our product life cycle.

- (3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.
- (4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.
- (6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74LV165A-EP:

Catalog: SN74LV165A

Automotive: SN74LV165A-Q1

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.



PACKAGE OPTION ADDENDUM

www.ti.com 11-Nov-2025

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects



SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you fully indemnify TI and its representatives against any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale, TI's General Quality Guidelines, or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products. Unless TI explicitly designates a product as custom or customer-specified, TI products are standard, catalog, general purpose devices.

TI objects to and rejects any additional or different terms you may propose.

Copyright © 2025, Texas Instruments Incorporated

Last updated 10/2025